

Title (en)

Integrated circuit with integrated test aid sub-circuit

Title (de)

Integrierte Schaltung mit integrierter Testhilfe-Teilschaltung

Title (fr)

Commutation intégrée dotée d'une commutation partielle de programme d'aide à la mise au point

Publication

**EP 1783779 B1 20080702 (DE)**

Application

**EP 06022111 A 20061021**

Priority

DE 102005052269 A 20051027

Abstract (en)

[origin: EP1783779A1] The circuit has a digital input (12) with a circuit section (34) that includes a current-voltage characteristic that holds a voltage at the input at a defined value in the absence of an input signal. Another circuit section provides an internal signal that is internal to the circuit, where state of the internal signal is not directly provided at an output of the circuit. The circuit section (34) has a control input (36) for a control signal, and is designed to change the current-voltage characteristic when the control signal is present at the control input. An independent claim is also included for a method for testing an integrated circuit.

IPC 8 full level

**G11C 29/46** (2006.01); **G11C 29/24** (2006.01); **G11C 29/44** (2006.01); **G11C 29/48** (2006.01)

CPC (source: EP US)

**G01R 31/31701** (2013.01 - EP US); **G11C 29/1201** (2013.01 - EP US); **G11C 29/48** (2013.01 - EP US)

Designated contracting state (EPC)

DE FR

DOCDB simple family (publication)

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DOCDB simple family (application)

**EP 06022111 A 20061021**; DE 102005052269 A 20051027; DE 502006001021 T 20061021; US 58671006 A 20061026